

L Number	Hits	Search Text	DB	Time stamp
-	56	semiconductor adj substrate and inductor and capacitor and radio adj frequency and etching and monitoring	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:36
-	130	(438/8).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:26
-	114	(438/13).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:28
-	259	radio adj frequency adj detection or radio adj frequency adj detector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:30
-	17251	chemical adj etching	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:48
-	1	(radio adj frequency adj detection or radio adj frequency adj detector) and (chemical adj etching)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:33
-	141	lateral adj undercut	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:36
-	15708	resonate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:36
-	110	(chemical adj etching) and resonate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:36
-	1133640	semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:36
-	41	((chemical adj etching) and resonate) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:40
-	130	quartz adj crystal adj monitor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:45

-	165128	receiver and transmitter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:46
-	185	(chemical adj etching) and (receiver and transmitter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 16:46
-	2	5629244.URPN.	USPAT	2002/05/17 17:06
-	22	5639423.URPN.	USPAT	2002/05/17 17:10
-	30	("4219335"   "4596697"   "4598049"   "4632808"   "4673657"   "4676274"   "4683195"   "4708931"   "4737464"   "4759828"   "4908112"   "4920056"   "4952266"   "4960486"   "4963498"   "5000817"   "5003822"   "5006749"   "5129262"   "5212988"   "5220189"   "5229297"   "5252294"   "5270183"   "5296375"   "5304487"   "5385709"   "5427946"   "5486335"   "5498392").PN.	USPAT	2002/05/17 17:12
-	5	5282921.URPN.	USPAT	2002/05/17 17:16
-	5	("2912497"   "2967907"   "3806643"   "4423137"   "4509162").PN.	USPAT	2002/05/17 17:17
-	256	(438/381).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:24
-	48	rf adj etch	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:41
-	5	5817573.URPN.	USPAT	2002/05/17 17:38
-	5	5817573.URPN.	USPAT	2002/05/17 17:38
-	14	("5141897"   "5167760"   "5231051"   "5233223"   "5254498"   "5312773"   "5326427"   "5358621"   "5364817"   "5374849"   "5387550"   "5397742"   "5407861"   "5496773").PN.	USPAT	2002/05/17 17:38
-	1	"non-contact detection system" and (etch or etching)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:43
-	435	high adj frequency adj detection or high adj frequency adj detector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:44
-	330600	etch or etching	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:45
-	653629	silicon	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:45

-	6	(high adj frequency adj detection or high adj frequency adj detector) and (etch or etching) and silicon	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:45
-	0	chemical adj etching and (high adj frequency adj detection or high adj frequency adj detector)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/17 17:48
-	1	"secondary ion emission spectroscopy"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:03
-	8	"leybold-inficon"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:04
-	405	radio adj waves and etching	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:05
-	1133640	semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:06
-	193	(radio adj waves and etching) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:42
-	0	(156/627.1).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:42
-	0	(156/627).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:46
-	2	("6210981").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 11:55
-	5	("5140164"   "5629244"   "5733820"   "5821549"   "5844416").PN.	USPAT	2002/05/19 11:46
-	18	("4639301"   "4818872"   "4843330"   "4851097"   "4875971"   "4912327"   "4924287"   "4943769"   "4954773"   "4996659"   "5057773"   "5089774"   "5140164"   "5155368"   "5376883"   "5430305"   "5521517"   "5525806").PN.	USPAT	2002/05/19 11:47
-	5	5844416.URPN.	USPAT	2002/05/19 11:49
-	3	6210981.URPN.	USPAT	2002/05/19 11:50
-	9	("5127984"   "RE34425"   "5268065"   "5413941"   "5433650"   "5433651"   "5856871"   "5891352"   "6210981").PN.	USPAT	2002/05/19 11:52
-	0	6368881.URPN.	USPAT	2002/05/19 11:54

3	("5516339").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 11:56
2	5516339.URPN.		
31	("4303748"   "4547440"   "4556614"   "4589197"   "4594299"   "4631810"   "4638407"   "4654279"   "4683181"   "4722877"   "4748542"   "4758483"   "4792504"   "4818643"   "4822701"   "4830939"   "4902589"   "4908283"   "4911995"   "4925751"   "4935317"   "4997732"   "5009970"   "5011501"   "5013619"   "5037712"   "5041346"   "5089027"   "5102752"   "5176968"   "5409786").PN.	USPAT	2002/05/19 11:55 2002/05/19 11:55
1	"thickness detection" same radio	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 11:58
4	"thickness detection" same rf	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 11:58
14	"insitu" and etching and (rf or radio) and (monitoring or detection)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:03
6	("4115184"   "4207137"   "4354154"   "4963819"   "5175472"   "5273610").PN.	USPAT	2002/05/19 12:08
29	5467013.URPN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:09 2002/05/19 12:33
144	"lateral undercut" or "lateral under-cut"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:45
5	(("6063642") or ("5559058")).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:45
0	("physical adj measured and undercut").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:46
0	("physical adj measured same undercut").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:46
0	("physical adj measured same "undercut").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:46
0	("undercut").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2002/05/19 12:46

-	43622	undercut	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:33
-	1134671	measured	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:47
-	4169	undercut and measured	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:47
-	653629	silicon	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:47
-	1209	(undercut and measured ) and silicon	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:47
-	596606	lateral	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:48
-	422	((undercut and measured ) and silicon ) and lateral	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:48
-	1969	insitu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 12:48
-	1	((((undercut and measured ) and silicon ) and lateral) and insitu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:32
-	3	("4763183"   "5114233"   "5539766").PN.	USPAT	2002/05/19 13:03
-	5	5739909.URPN.	USPAT	2002/05/19 13:04
-	252	(324/329).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:32
-	57	(324/341).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:32
-	264	(324/338).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:32

-	9	(324/364).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:33
-	301	(324/71.5).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:33
-	609	undercut and ((324/329).CCLS.) or ((324/341).CCLS.) or ((324/338).CCLS.) or ((324/364).CCLS.) or ((324/71.5).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:34
-	88	silicon and (undercut and ((324/329).CCLS.) or ((324/341).CCLS.) or ((324/338).CCLS.) or ((324/364).CCLS.) or ((324/71.5).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/19 13:34
-	2	5027064.URPN.	USPAT	2002/05/19 13:42